

PROPOSAL FOR TECHNICAL COMMITTEE WORK ITEM
NCITS 322 REVISION - TEST METHODS FOR CARD DURABILITY

Prepared by:

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1. IDENTIFICATION OF PROJECT

1.1 Title: NCITS 322 - Card Durability Test Methods Update

1.2 Proposers: Brad Paulson Thor Engineering (507) 663-0107
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1.3 Submitted: June 29, 2001

1.4 Project Type: D

2. JUSTIFICATION OF PROPOSED STANDARD

2.1 Needs:

Since the publication of NCITS 322 in 1998, additional test methods and refinements of the published test methods have been proposed. NCITS B10.3 wishes to open the document for revision.

2.2 Recommended Scope of Standard:

Further refinements of the physical durability test methods for ID cards are desired. (ID cards as defined in ISO/IEC 781X series standards.) The refinements of the test methods may include the following parameters:

Flexure
Static Stress
Abrasion Resistance
Impact Resistance
Dye Migration
Daylight/UV Light Fading

2.3 Existing Practice in Area of Proposed Standard:

NCITS 322 has become a recognized source for card durability test methods. It has been referenced in NCITS B10.8 working paper regarding driver license requirements.

2.4 Expected Stability of Proposed Standard:

The proposed Test Methods document, which addresses overall durability parameters for ID cards, is expected to provide important information for at least 10 additional years.

3. DESCRIPTION OF PROPOSED PROJECT

3.1 Type of Document: Standard – Revision of NCITS 322

3.2 Definitions of Concepts and Special Terms:
None

3.3 Expected Relationship with Approved X3 Reference Models:
Not applicable

3.4 Recommended Program of Work:
NCITS 322 document update is expected to be completed in 2 years.

3.5 Resources - Individual and Organization Competent in Subject Matter:
Besides the proposers, many persons recognized as competent in the subject matter have expressed interest in working on this document update. They represent organizations listed below:

3M Company
DataCard Corp.
Plastag
MBNA America
MagTek
Waytek
Qualteq

3.6 Recommended Development Technical Committee: B10

3.7 Anticipated Frequency and Duration of Meetings:
Meetings would be planned to take place prior to B10.3 meetings, which historically meets 3 times per year.

3.8 Target Date for dpANS to X3: 2 years

3.9 Estimated Useful Life of Standard: At least 10 years

4. IMPLEMENTATION IMPACTS

4.1 Impact on Existing User Practices and Investment:

Very little, if any. Additional investment in Test Equipment may be required to those who wish to perform card testing.

4.2 Impact on Supplier Products and Support:

Only positive impacts are foreseen. Once industry recognized performance testing is established, suppliers may wish to provide a range of card products that are differentiated by performance measures.

4.3 Techniques and Costs for Compliance Verification:

None required. The proposal is only to establish durability Test Methods. No specific performance standard is included for this work item. Thus verification is not applicable.

4.4 Legal Considerations: None Known

5. CLOSELY RELATED STANDARDS ACTIVITIES

5.1 Existing Standards:

ISO/IEC 7810	Identification cards - Physical characteristics
ISO/IEC 7811 (parts 1-6)	Identification cards - Recording technique
ISO/IEC 10373 (parts 1-6)	Identification cards - Test Methods

5.2 NCITS Standards Development Projects: None

5.3 NCITS/OMC Study Groups: None

5.4 Other Related Domestic Standard Efforts: None

5.5 ISO Standards Development Projects: None

5.6 Other Related International Standards Development Projects: None

5.7 Recommendations for Coordinating Liaison: None

5.8 Recommendations for Close Liaison: None